

Search Notes

Application/Control No.

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Examiner

Anh T.N. Vo

Applicant(s)/Patent under
Reexamination

HAAN ET AL.

Art Unit

2861

SEARCHED

Class	Subclass	Date	Examiner
npcl/ndcl Search 10/05/05			

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR